S	earcn	Notes	

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/568,289	FUJITA ET AL.	
Examiner	Art Unit	
Charlie Bana	2883	

SEARCHED			
Class	Subclass	Date	Examiner
	<u> </u>		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		*	
	1.	<del>.</del>	
			į
		;	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
385 subclasses (text search only - see search history printout)	6/4/2007	СҮР
EAST (USPT, USPGPub, USOCR, JPO, EPO, Derwent, IBM_TDB) - See attached EAST search history printout	6/4/2007	CYP
Applicant(s) name(s) searched for double patenting - See attached PALM search history printout	6/4/2007	СҮР
<del></del>		
		•